SIEMENS

Finally – an easy-to-use X-ray diffraction system for analyzing polymers

The Siemens Area Detector and GADDS (General Area Detector Diffraction System) polymer software are faster, more flexible and easier to run than any other X-ray diffraction system available today. Featuring pop-up menus and real-time color display as part of a graphics-oriented user interface, the only thing missing is competition.

- Ideal for texture analysis, percent crystallinity and other applications, including QC

- Easily measures d-spacings, angles and intensities from any pixel location

- Versatile data files can be used with powder diffraction software for phase identification and profile fitting

Plastics

True QC instrument for measuring intensities and d-spacings resulting from different draw rates or annealing temperatures
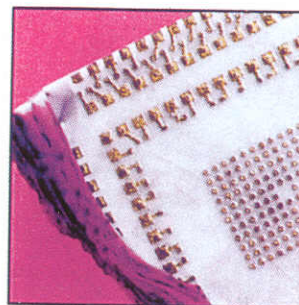
Texture

Measures scattering from amorphous through polycrystalline to 3-D single-crystalline with a powerful scripting feature

Composites

Versatile analysis of composite bondings with use of the system as an X-ray probe

CLRC